

# 2017 Accelerated Stress Testing and Reliability (ASTR) Conference

Sponsored by IEEE Reliability Society and ASQ Reliability Division

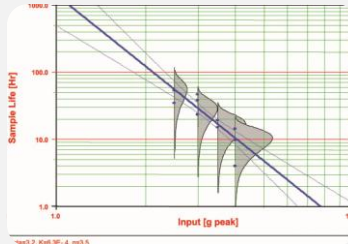
## CALL FOR PAPERS AND PRESENTATIONS

### Mitigating Risk Through Accelerated Life Testing

September 27 – 29, 2017

Hilton Garden Inn Downtown, Austin, Texas

[www.ieee-astr.org](http://www.ieee-astr.org)



The 2017 Accelerated Stress Testing and Reliability (ASTR) Conference is focused on highlighting cutting-edge methods to deliver maximum cost-benefits from accelerated reliability testing. ASTR 2017 is relevant to product development, test and manufacturers involved in the aerospace, automotive, consumer electronics, defense, medical, telecommunications and other cutting edge industries where reliability is a key driver of operational and business success. ASTR 2017 will present detailed case studies, best practices, lessons learned, and clear insight on how to best apply and integrate accelerated testing tools and methods.

### **Abstracts are invited now with a 150 words summary due by March 15!**

The 2017 focus will include (but not limited to):

- The science of test acceleration: integration of design modeling, analysis and accelerated testing
- New Accelerated Test Standards in progress
- Effects of corrosion and high energy radiation on reliability
- Highly Accelerated Life Testing (HALT) and Highly Accelerated Stress Screening (HASS)

Complete submission details are available at [http://ieee-astr.org/ASTR\\_Technical\\_program.php](http://ieee-astr.org/ASTR_Technical_program.php).

OR send proposed papers to [charles.recchia@ieee.org](mailto:charles.recchia@ieee.org)

Become part of this active, growing conference sponsored by both the ASQ-Reliability Division and the IEEE-Reliability Society. The hotel has **special rates** for this conference.

*There are many reasons to attend this conference! Make this your fall destination:*

- Visit a local technology company
- Learn new techniques
- Accelerated Test
- High Tech city
- Life Testing
- Robustness Testing